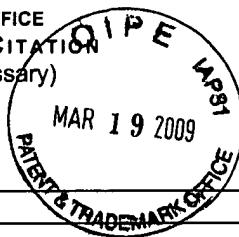


FORM HDP-1449 (Based on Form PTO-1449)

PATENT AND TRADEMARK OFFICE
INFORMATION DISCLOSURE CITATION
 (Use several sheets if necessary)

Sheet 1 of 7



ATTORNEY DOCKET NO.	SERIAL No.
1740-000121/US	10/516,910
APPLICANT	
Sang Woon SUH et al.	
FILING DATE	GROUP
May 9, 2005	2431

U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1		7,266,074	09-04-2007	Kim et al.		
2		6,938,162	08-30-2005	Nagai et al.		
3		6,930,977	08-16-2005	Kondo et al.		
4		2005/0122889 A1	06-09-2005	Kobayashi et al.		
5		2005/0099916 A1	05-12-2005	Jeon et al.		
6		6,885,629	04-26-2005	Oshima et al.		
7		2005/0018555 A1	01-27-2005	Sabi et al.		
8		2004/0151091 A1	08-05-2004	Ma et al.		
9		2004/0120247 A1	06-24-2004	Lee et al.		
10		2004/0076110 A1	04-22-2004	Hino et al.		
11		6,664,526	12-16-2003	Yokoi		
12		2003/0117920 A1	06-26-2003	Sako et al.		
13		6,550,009	04-15-2003	Uranaka et al.		
14		6,549,495	04-15-2003	Spruit et al.		
15		6,538,982	03-25-2003	Van Vlerken et al.		
16		2003/0053404 A1	03-20-2003	Kondo		
17		6,519,213	02-11-2003	Song et al.		
18		2002/0181358 A1	12-05-2002	Sako		
19		2002/0089920 A1	07-11-2002	Gotoh et al.		
20		2002/0048241 A1	04-25-2002	Kumagai et al.		
21		2002/0041686 A1	04-11-2002	Moriyama et al.		
22		6,353,890	03-05-2002	Newman		
23		2001/0036132 A1	11-01-2001	Kobayashi et al.		
24		6,223,285	04-24-2001	Komuro et al.		

Examiner:

Date Considered:

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) Sheet 2 of 7		ATTORNEY DOCKET NO.	SERIAL NO.
		1740-000121/US	10/516,910
		APPLICANT	
		Sang Woon SUH et al.	
		FILING DATE	GROUP
		May 9, 2005	2431

U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
25		6,223,247	04-24-2001	Otsuka et al.		
26		6,031,815	02-29-2000	Heemskerk		
27		6,021,199	02-01-2000	Ishibashi		
28		5,894,463	04-13-1999	Okawa et al.		
29		5,878,007	03-02-1999	Matsumoto et al.		
30		5,848,050	12-08-1998	Nagasawa et al.		
31		5,818,805	10-06-1998	Kobayashi et al.		
32		5,809,006	09-15-1998	Davis et al.		
33		5,799,501	09-01-1998	Leonard et al.		
34		5,706,268	01-06-1998	Horimai		
35		5,689,486	11-18-1997	Shimizu et al.		
36		5,572,507	11-05-1996	Ozaki et al.		
37		5,295,127	03-15-1994	Verboom et al.		
38		4,879,707	11-07-1989	Getreuer et al.		

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
39		CN 1362707	08-07-2002	China		Abstract
40		CN 1293810	05-02-2001	China		Abstract
41		CN 1152170	06-18-1997	China		Abstract
42		EP 1 028 423 B1	03-17-2004	EPO		

Examiner:	Date Considered:
-----------	------------------

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITIGATION (Use several sheets if necessary) Sheet 3 of 7	ATTORNEY DOCKET No.	SERIAL No.
	1740-000121/US	10/516,910
	APPLICANT	
	Sang Woon SUH et al.	
	FILING DATE	GROUP
	May 9, 2005	2431

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
43		EP 1 229 537 A2	08-07-2002	EPO		
44		EP 1 168 328 A1	01-02-2002	EPO		
45		EP 1 168 312 A1	01-02-2002	EPO		
46		EP 1 152 412 A1	11-07-2001	EPO		
47		EP 1 122 729 A1	08-08-2001	EPO		
48		EP 0 807 929 B1	02-28-2001	EPO		
49		EP 1 067 540 A2	01-10-2001	EPO		
50		EP 1 058 254 B1	12-06-2000	EPO		
51		EP 0 997 899 A2	05-03-2000	EPO		
52		EP 0 936 610 A2	08-18-1999	EPO		
53		EP 0 545 472 B1	06-09-1993	EPO		
54		EP 0 299 573 A1	07-08-1988	EPO		
55		JP 2002-367281	12-20-2002	Japan		Abstract
56		JP 2003-006997	01-10-2003	Japan		Abstract
57		JP 2002-319245	10-31-2002	Japan		Abstract
58		JP 2002-304809	10-18-2002	Japan		Abstract
59		JP 2002-216360	08-02-2002	Japan		Abstract
60		JP 2002-197789	07-12-2002	Japan		Abstract
61		JP 2002-197674	07-12-2002	Japan		Abstract
62		JP 2002-163857	06-07-2002	Japan		Abstract
63		JP 2002-042347	02-08-2002	Japan		Abstract

Examiner:	Date Considered:
-----------	------------------

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) Sheet 4 of 7	ATTORNEY DOCKET NO.	SERIAL No.
	1740-000121/US	10/516,910
	APPLICANT	
	Sang Woon SUH et al.	
	FILING DATE	GROUP
	May 9, 2005	2431

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
64		JP 2001-332031	11-30-2001	Japan		Abstract
65		JP 2001-256678	09-21-2001	Japan		Abstract
66		JP 2001-243355	09-07-2001	Japan		Abstract
67		JP 2001-0189051	07-10-2001	Japan		Abstract
68		JP 2001-167517	06-22-2001	Japan		Abstract
69		JP 2000-298941	10-24-2000	Japan		Abstract
70		JP 2000-195094	07-14-2000	Japan		Abstract
71		JP 2000-195049	07-14-2000	Japan		Abstract
72		JP 2000-149415	05-30-2000	Japan		Abstract
73		JP 11-317002	11-16-1999	Japan		Abstract
74		JP 11-261950	09-24-1999	Japan		Abstract
75		JP 11-086436	03-30-1999	Japan		Abstract
76		JP 10-269577	10-09-1998	Japan		Abstract
77		JP 10-003746	01-06-1998	Japan		Abstract
78		JP 09-128874	05-16-1997	Japan		Abstract
79		JP 09-081938	03-28-1997	Japan		Abstract
80		JP 08-147704	06-07-1996	Japan		Abstract
81		JP 08-124171	05-17-1996	Japan		Abstract
82		JP 07-272282	10-20-1995	Japan		Abstract
83		JP 05-325193	12-10-1993	Japan		Abstract
84		JP 05-036194	02-12-1993	Japan		Abstract

Examiner:	Date Considered:
-----------	------------------

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) Sheet 5 of 7	ATTORNEY DOCKET NO.	SERIAL NO.
	1740-000121/US	10/516,910
	APPLICANT	
	Sang Woon SUH et al.	
	FILING DATE	GROUP
	May 9, 2005	2431

FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No
85		KR 10-2004-0048476	06-10-2004	Korea		Abstract
86		WO 2004/095439 A1	11-04-2004	WIPO		
87		WO 02/37493 A1	05-10-2002	WIPO		Abstract
88		WO 02/31821 A1	04-18-2002	WIPO		Abstract
89		WO 02/15183 A2	02-21-2002	WIPO		
90		WO 97/45836	12-04-1997	WIPO		

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)	
Ref. Desig.	Examiner's Initials
91	Office Action issued December 19, 2008 by the Chinese Patent Office in Chinese Patent Application No. 200480000399.8 (with English language translation)
92	Office Action issued July 4, 2008 by the Chinese Patent Office in Chinese Patent Application No. 200610059757.3 (with English language translation)
93	Office Action issued September 1, 2006 by the Chinese Patent Office in Chinese Patent Application No. 200480000399.8 (with English language translation)
94	Supplemental Search Report issued April 2, 2008 by the European Patent Office in European Patent Application No. 04703277.6-2223
95	Extended Search Report issued March 26, 2008 by the European Patent Office in European Patent Application No. 07018405.6-2223
96	Office Action issued March 12, 2008 by the European Patent Office in European Patent Application No. 04703529.0-1232
97	Extended Search Report issued November 7, 2007 by the European Patent Office in European Patent Application No. 07018289.4-1232
98	Office Action issued October 29, 2007 by the European Patent Office in European Patent Application No. 06001616.9-1232
99	Supplemental Search Report issued November 24, 2006 by the European Patent Office in European Patent Application No. 04705015.8-2223
100	Extended Search Report issued September 22, 2006 by the European Patent Office in European Patent Application No. 06001615.1-2223

Examiner:	Date Considered:
-----------	------------------

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) Sheet 6 of 7	ATTORNEY DOCKET NO.	SERIAL NO.
	1740-000121/US	10/516,910
	APPLICANT	
	Sang Woon SUH et al.	
	FILING DATE	GROUP
May 9, 2005	2431	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
101		Supplemental Search Report issued September 22, 2006 by the European Patent Office in European Patent Application No. 04703531.6-2223
102		Supplemental Search Report issued June 12, 2006 by the European Patent Office in European Patent Application No. 04703541.5-2210
103		Office Action issued August 20, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-076406
104		Office Action issued August 19, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-500635
105		Office Action issued March 24, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-500637
106		Office Action issued March 17, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-500638
107		Office Action issued January 16, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-500639
108		Office Action issued January 16, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-500635
109		Office Action issued January 16, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-076406
110		Office Action issued January 16, 2008 by the Japanese Patent Office in Japanese Patent Application No. 2006-076383
111		Office Action issued August 24, 2007 by the Japanese Patent Office in Japanese Patent Application No. 2006-500638
112		Office Action issued March 30, 2006 by the Korean Patent Office in Korean Patent Application No. 10-2003-0004487
113		Office Action issued March 28, 2005 by the Korean Patent Office in Korean Patent Application No. 10-2003-0004487
114		Office Action issued January 30, 2007 by the Russian Patent Office in Russian Patent Application No. 2006109209/28 (with English language translation)
115		Office Action issued July 10, 2007 by the Taiwanese Patent Office in Taiwanese Patent Application No. 095113498 (with English language translation)
116		Office Action issued November 14, 2008 by the USPTO in U.S. Patent Application No. 10/762,536
117		Office Action issued July 31, 2008 by the USPTO in U.S. Patent Application No. 11/898,040
118		Office Action issued June 6, 2008 by the USPTO in U.S. Patent Application No. 10/762,535

Examiner:
Date Considered:

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM HDP-1449 (Based on Form PTO-1449) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	ATTORNEY DOCKET NO.	SERIAL NO.
	1740-000121/US	10/516,910
	APPLICANT	
	Sang Woon SUH et al.	
FILING DATE	GROUP	
	May 9, 2005	2431

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Examiner: _____ Date Considered: _____

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.